

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

JPW

International Patent Application of

KUDOU, S. et al.

Atty. Ref.: 1417-459

Serial No. 10/820,151

TC/A.U.: 2877

Filed: April 8, 2004

Examiner:

For: METHOD AND APPARATUS FOR MEASURING THICKNESSES OF
LAYERS OF MULTILAYER THIN FILM

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August 24, 2004

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

INFORMATION DISCLOSURE STATEMENT

Attention is invited to the attached copy of a European Search Report mailed August 6, 2004 with respect to this disclosure and a copy of each document cited in it. A completed Form PTO-1449 is also attached.

Official citation and consideration of all the attached documents is requested. Please return to the undersigned a copy of the attached PTO-1449 with the examiner's initials in the left column [MPEP §609] with the next communication.

I hereby certify that each item of information contained herein was first cited in a communication from a foreign patent office in a counterpart foreign application not more than 3 months from the filing date of this statement [see 37 C.F.R. § 1.97(e) (1)].


The filing of an Information Disclosure Statement shall not be construed as a representation that a search has been made, an admission that the information cited is, or is considered to be, material to patentability [37 C.F.R. § 1.97(g) & (h)] or that no other material information exists.

The Commissioner is hereby authorized to charge our Deposit Account No. 14-1140 for any fees required in connection with the filing of this Information Disclosure Statement.

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Respectfully submitted,

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